Search i	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/686,467	FUWAUSA ET AL.
Examiner	Art Unit
Bao Q. Truong	2875

SEARCHED					
OLANOILE D					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
Quick update text search with ultraviolet, quartz, and semiconductor	2/23/2006	ВQТ		
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